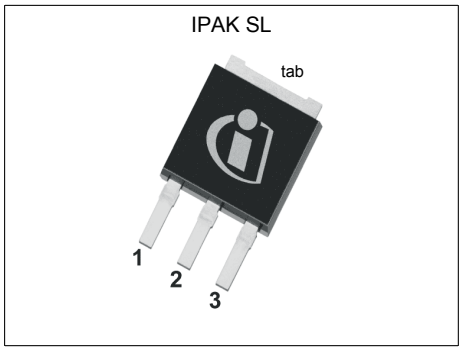
# MOSFET

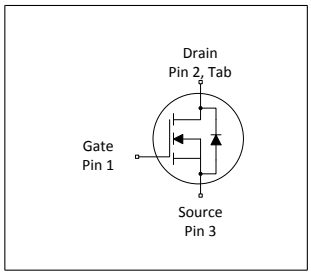
## 600V CoolMOS™ CE Power Transistor

CoolMOS™ is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies. CoolMOS™ CE is a price-performance optimized platform enabling to target cost sensitive applications in Consumer and Lighting markets by still meeting highest efficiency standards. The new series provides all benefits of a fast switching Superjunction MOSFET while not sacrificing ease of use and offering the best cost down performance ratio available on the market.




## Features

- Extremely low losses due to very low FOM Rdson*Qg and Eoss
- Very high commutation ruggedness
- Easy to use/drive
- Pb-free plating, Halogen free mold compound
- Qualified for standard grade applications




## Applications

PFC stages, hard switching PWM stages and resonant switching stages for e.g. PC Silverbox, Adapter, LCD & PDP TV and indoor lighting.

*Please note: For MOSFET paralleling the use of ferrite beads on the gate or separate totem poles is generally recommended.*

## Table 1 Key Performance Parameters

| Parameter | Value | Unit |
|---|---|---|
| $V_{DS}$ @ $T_{j,max}$ | 650 | V |
| $R_{DS(on),max}$ | 1500 | mΩ |
| $I_{d.}$ | 5 | A |
| $Q_{g.typ}$ | 9.4 | nC |
| $I_{D,pulse}$ | 8 | A |
| $E_{oss}$@400V | 1 | µJ |

| Type / Ordering Code | Package | Marking | Related Links |
|---|---|---|---|
| IPS60R1K5CE | PG-TO 251 | 60S1K5CE | see Appendix A |

## Table of Contents

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# 1 Maximum ratings

at $T_j$ = 25°C, unless otherwise specified

## Table 2 Maximum ratings

| Parameter | Symbol | Values | | | Unit | Note / Test Condition |
|---|---|---|---|---|---|---|
| | | Min. | Typ. | Max. | | |
| Continuous drain current[1] | $I_D$ | -<br>- | -<br>- | 5<br>3.2 | A | $T_C$=25°C<br>$T_C$=100°C |
| Pulsed drain current[2] | $I_{D,pulse}$ | - | - | 8 | A | $T_C$=25°C |
| Avalanche energy, single pulse | $E_{AS}$ | - | - | 26 | mJ | $I_D$=0.6A; $V_{DD}$=50V; see table 11 |
| Avalanche energy, repetitive | $E_{AR}$ | - | - | 0.09 | mJ | $I_D$=0.6A; $V_{DD}$=50V; see table 11 |
| Avalanche current, repetitive | $I_{AR}$ | - | - | 0.6 | A | - |
| MOSFET dv/dt ruggedness | dv/dt | - | - | 50 | V/ns | $V_{DS}$=0...480V |
| Gate source voltage (static) | $V_{GS}$ | -20 | - | 20 | V | static; |
| Gate source voltage (dynamic) | $V_{GS}$ | -30 | - | 30 | V | AC (f>1 Hz) |
| Power dissipation<br>TO-251 | $P_{tot}$ | - | - | 49 | W | $T_C$=25°C |
| Storage temperature | $T_{stg}$ | -40 | - | 150 | °C | - |
| Operating junction temperature | $T_j$ | -40 | - | 150 | °C | - |
| Continuous diode forward current | $I_S$ | - | - | 3.5 | A | $T_C$=25°C |
| Diode pulse current[2] | $I_{S,pulse}$ | - | - | 8 | A | $T_C$=25°C |
| Reverse diode dv/dt[3] | dv/dt | - | - | 15 | V/ns | $V_{DS}$=0...400V, $I_{SD}$<=$I_S$, $T_j$=25°C<br>see table 9 |
| Maximum diode commutation speed | $di_f/dt$ | - | - | 500 | A/µs | $V_{DS}$=0...400V, $I_{SD}$<=$I_S$, $T_j$=25°C<br>see table 9 |

# 2 Thermal characteristics

## Table 3 Thermal characteristics TO-251

| Parameter | Symbol | Values | | | Unit | Note / Test Condition |
|---|---|---|---|---|---|---|
| | | Min. | Typ. | Max. | | |
| Thermal resistance, junction - case | $R_{thJC}$ | - | - | 2.57 | °C/W | - |
| Thermal resistance, junction - ambient | $R_{thJA}$ | - | - | 62 | °C/W | leaded |
| Soldering temperature, wavesoldering only allowed at leads | $T_{sold}$ | - | - | 260 | °C | 1.6mm (0.063 in.) from case for 10s |

[1] Limited by $T_{j\,max}$. Maximum duty cycle D=0.50
[2] Pulse width $t_p$ limited by $T_{j,max}$
[3] Identical low side and high side switch with identical $R_G$

# 3 Electrical characteristics

at $T_j$=25°C, unless otherwise specified

## Table 4 Static characteristics

| Parameter | Symbol | Values | | | Unit | Note / Test Condition |
|---|---|---|---|---|---|---|
| | | Min. | Typ. | Max. | | |
| Drain-source breakdown voltage | $V_{(BR)DSS}$ | 600 | - | - | V | $V_{GS}$=0V, $I_D$=0.25mA |
| Gate threshold voltage | $V_{(GS)th}$ | 2.5 | 3.0 | 3.5 | V | $V_{DS}$=$V_{GS}$, $I_D$=0.09mA |
| Zero gate voltage drain current | $I_{DSS}$ | -<br>- | -<br>10 | 1<br>- | µA | $V_{DS}$=600, $V_{GS}$=0V, $T_j$=25°C<br>$V_{DS}$=600, $V_{GS}$=0V, $T_j$=150°C |
| Gate-source leakage current | $I_{GSS}$ | - | - | 100 | nA | $V_{GS}$=20V, $V_{DS}$=0V |
| Drain-source on-state resistance | $R_{DS(on)}$ | -<br>- | 1.26<br>3.28 | 1.50<br>- | Ω | $V_{GS}$=10V, $I_D$=1.1A, $T_j$=25°C<br>$V_{GS}$=10V, $I_D$=1.1A, $T_j$=150°C |
| Gate resistance | $R_G$ | - | 14 | - | Ω | $f$=1MHz, open drain |

## Table 5 Dynamic characteristics

| Parameter | Symbol | Values | | | Unit | Note / Test Condition |
|---|---|---|---|---|---|---|
| | | Min. | Typ. | Max. | | |
| Input capacitance | $C_{iss}$ | - | 200 | - | pF | $V_{GS}$=0V, $V_{DS}$=100V, $f$=1MHz |
| Output capacitance | $C_{oss}$ | - | 16 | - | pF | $V_{GS}$=0V, $V_{DS}$=100V, $f$=1MHz |
| Effective output capacitance, energy related[1)] | $C_{o(er)}$ | - | 11 | - | pF | $V_{GS}$=0V, $V_{DS}$=0...480V |
| Effective output capacitance, time related[2)] | $C_{o(tr)}$ | - | 41.3 | - | pF | $I_D$=constant, $V_{GS}$=0V, $V_{DS}$=0...480V |
| Turn-on delay time | $t_{d(on)}$ | - | 8 | - | ns | $V_{DD}$=400V, $V_{GS}$=10V, $I_D$=1.4A, $R_G$=12.2Ω; see table 10 |
| Rise time | $t_r$ | - | 7 | - | ns | $V_{DD}$=400V, $V_{GS}$=10V, $I_D$=1.4A, $R_G$=12.2Ω; see table 10 |
| Turn-off delay time | $t_{d(off)}$ | - | 40 | - | ns | $V_{DD}$=400V, $V_{GS}$=10V, $I_D$=1.4A, $R_G$=12.2Ω; see table 10 |
| Fall time | $t_f$ | - | 20 | - | ns | $V_{DD}$=400V, $V_{GS}$=10 V, $I_D$=1.4A, $R_G$=12.2Ω; see table 10 |

## Table 6 Gate charge characteristics

| Parameter | Symbol | Values | | | Unit | Note / Test Condition |
|---|---|---|---|---|---|---|
| | | Min. | Typ. | Max. | | |
| Gate to source charge | $Q_{gs}$ | - | 1.1 | - | nC | $V_{DD}$=480V, $I_D$=1.4A, $V_{GS}$=0 to 10V |
| Gate to drain charge | $Q_{gd}$ | - | 5 | - | nC | $V_{DD}$=480V, $I_D$=1.4A, $V_{GS}$=0 to 10V |
| Gate charge total | $Q_g$ | - | 9.4 | - | nC | $V_{DD}$=480V, $I_D$=1.4A, $V_{GS}$=0 to 10V |
| Gate plateau voltage | $V_{plateau}$ | - | 5.4 | - | V | $V_{DD}$=480V, $I_D$=1.4A, $V_{GS}$=0 to 10V |

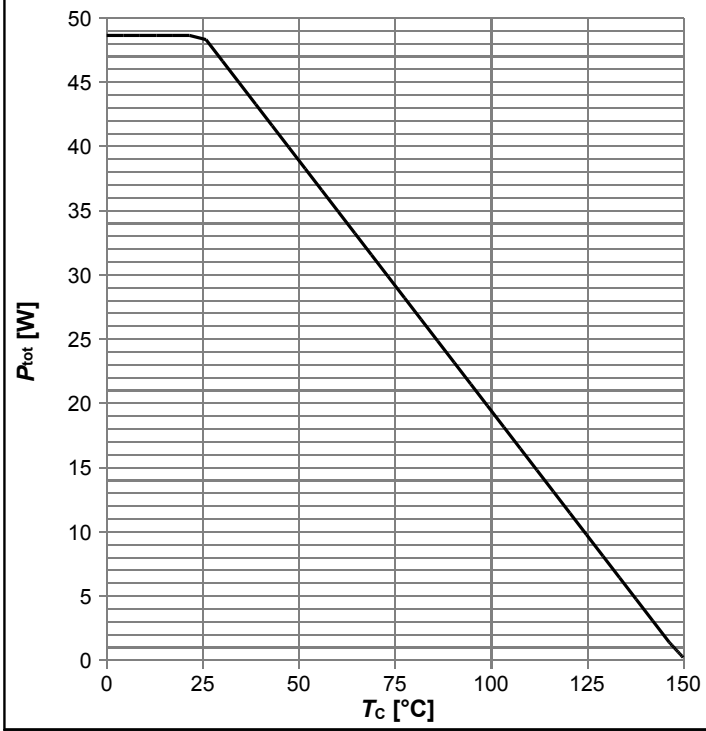
[1)] $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as $C_{oss}$ while $V_{DS}$ is rising from 0 to 80% $V_{o(BR)DSS}$
[2)] $C_{o(tr)}$ is a fixed capacitance that gives the same stored energy as $C_{oss}$ while $V_{DS}$ is rising from 0 to 80% $V_{o(BR)DSS}$

## Table 7 Reverse diode characteristics

| Parameter | Symbol | Values | | | Unit | Note / Test Condition |
|---|---|---|---|---|---|---|
| | | Min. | Typ. | Max. | | |
| Diode forward voltage | $V_{SD}$ | - | 0.9 | - | V | $V_{GS}$=0V, $I_F$=1.4A, $T_j$=25°C |
| Reverse recovery time | $t_{rr}$ | - | 230 | - | ns | $V_R$=400V, $I_F$=1.4A, d$i_F$/d$t$=100A/µs; see table 9 |
| Reverse recovery charge | $Q_{rr}$ | - | 1.1 | - | µC | $V_R$=400V, $I_F$=1.4A, d$i_F$/d$t$=100A/µs; see table 9 |
| Peak reverse recovery current | $I_{rrm}$ | - | 9.8 | - | A | $V_R$=400V, $I_F$=1.4A, d$i_F$/d$t$=100A/µs; see table 9 |

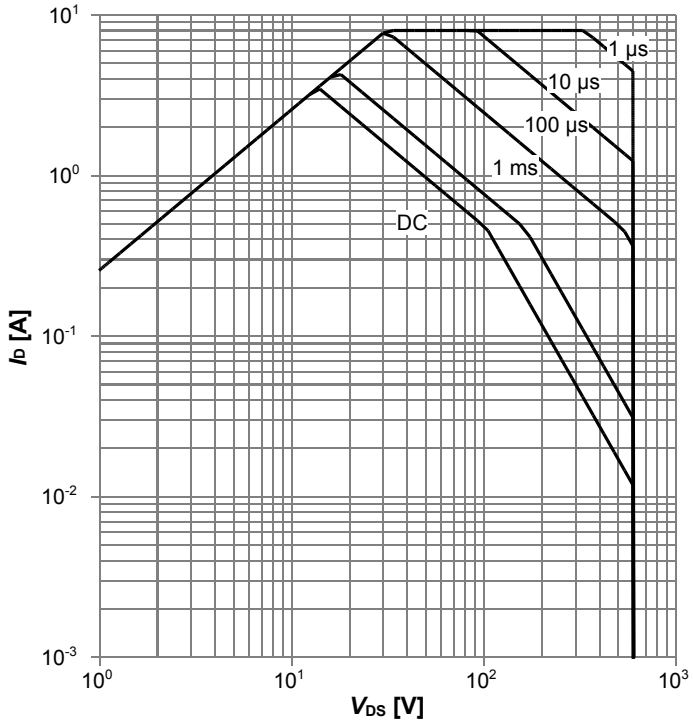
# 4 Electrical characteristics diagrams

**Diagram 1: Power dissipation (Non FullPAK)**



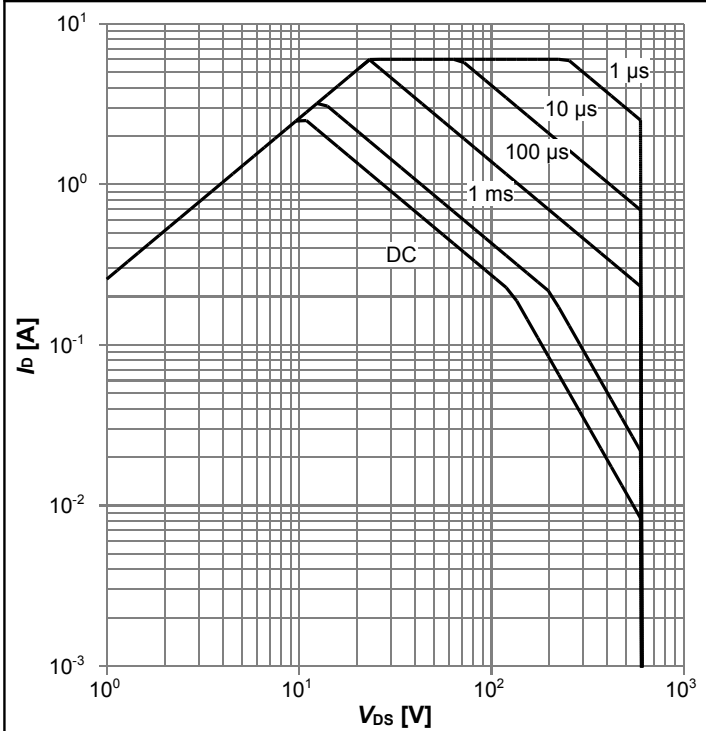

$P_{tot}$=f($T_C$)

**Diagram 2: Safe operating area (Non FullPAK)**



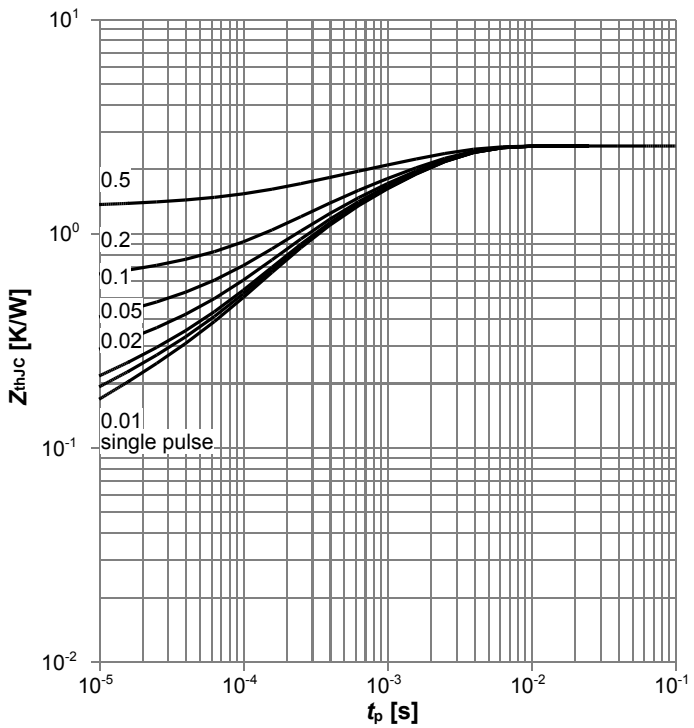

$I_D$=f($V_{DS}$); $T_C$=25 °C; $D$=0; parameter: $t_p$

**Diagram 3: Safe operating area (Non FullPAK)**



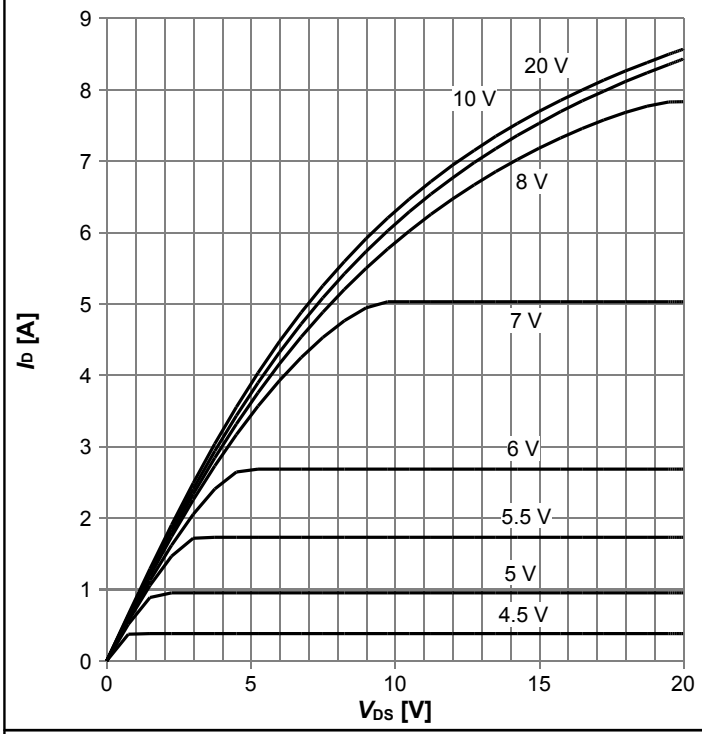

$I_D$=f($V_{DS}$); $T_C$=80 °C; $D$=0; parameter: $t_p$

**Diagram 4: Max. transient thermal impedance (Non FullPAK)**



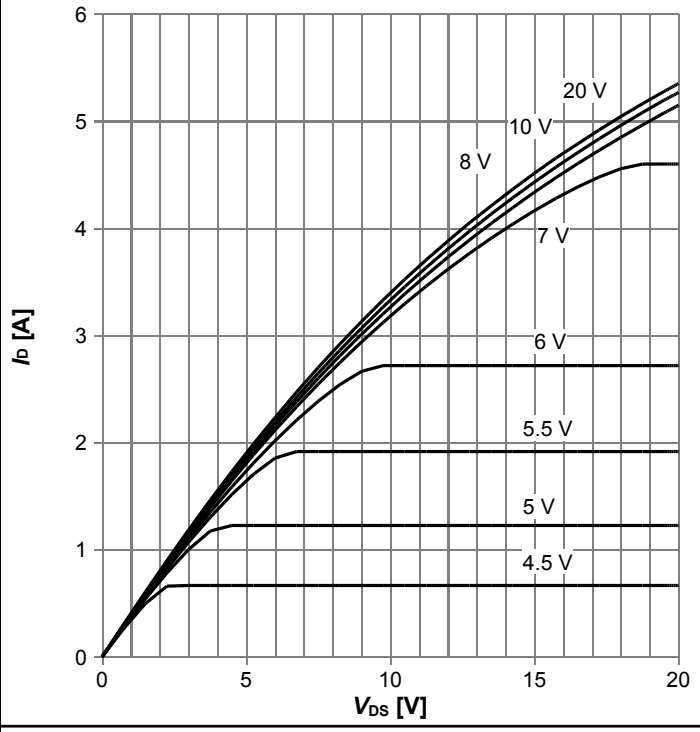

$Z_{thJC}$ =f($t_P$); parameter: $D$=$t_p$/$T$

**Diagram 5: Typ. output characteristics**



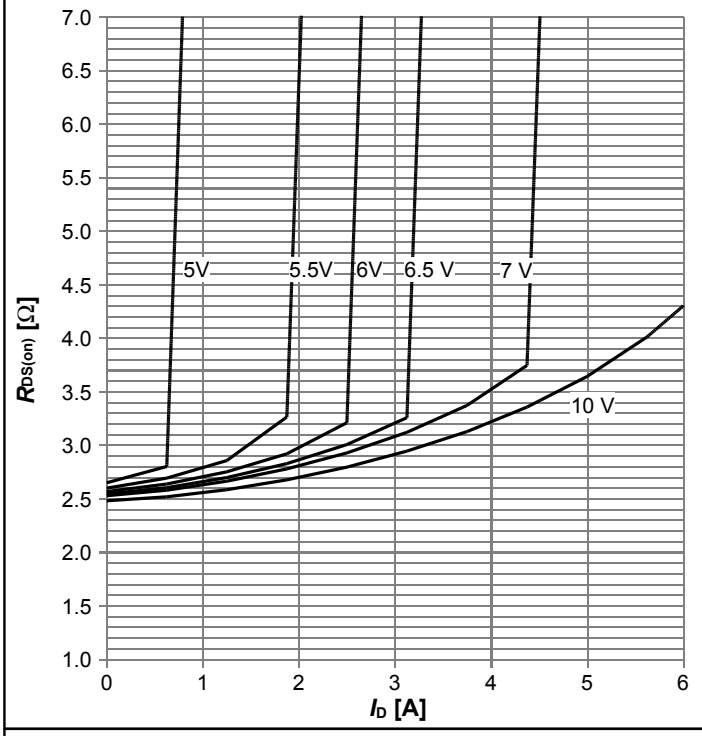

$I_D=f(V_{DS})$; $T_j=25$ °C; parameter: $V_{GS}$

**Diagram 6: Typ. output characteristics**



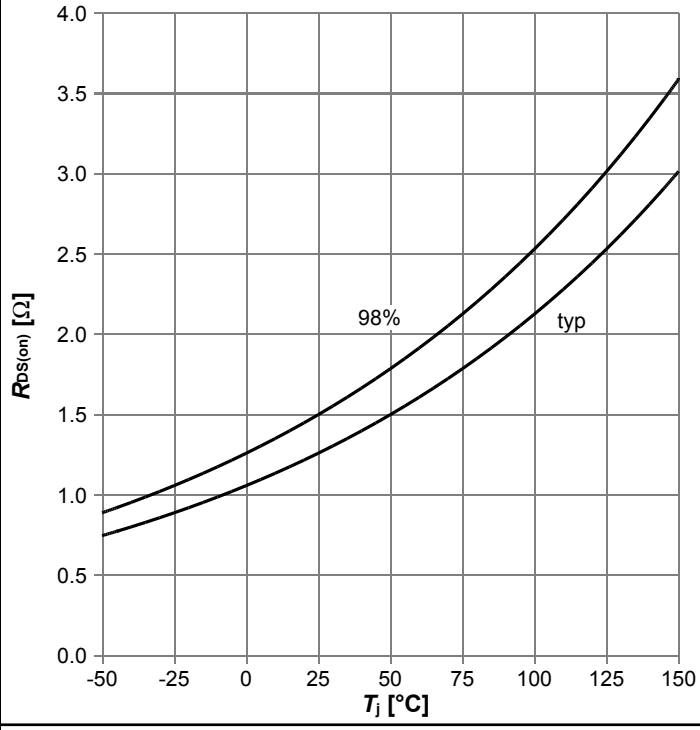

$I_D=f(V_{DS})$; $T_j=125$ °C; parameter: $V_{GS}$

**Diagram 7: Typ. drain-source on-state resistance**



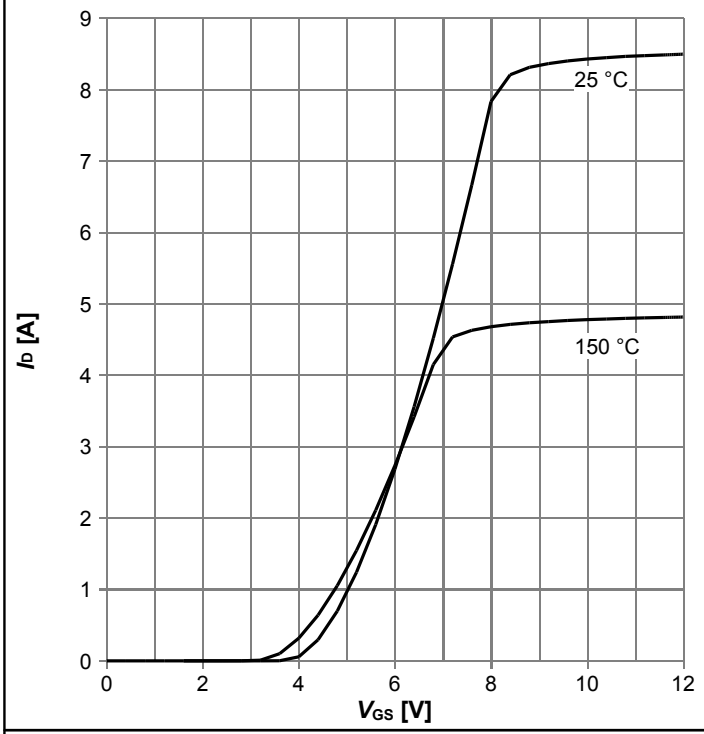

$R_{DS(on)}=f(I_D)$; $T_j=125$ °C; parameter: $V_{GS}$

**Diagram 8: Drain-source on-state resistance**



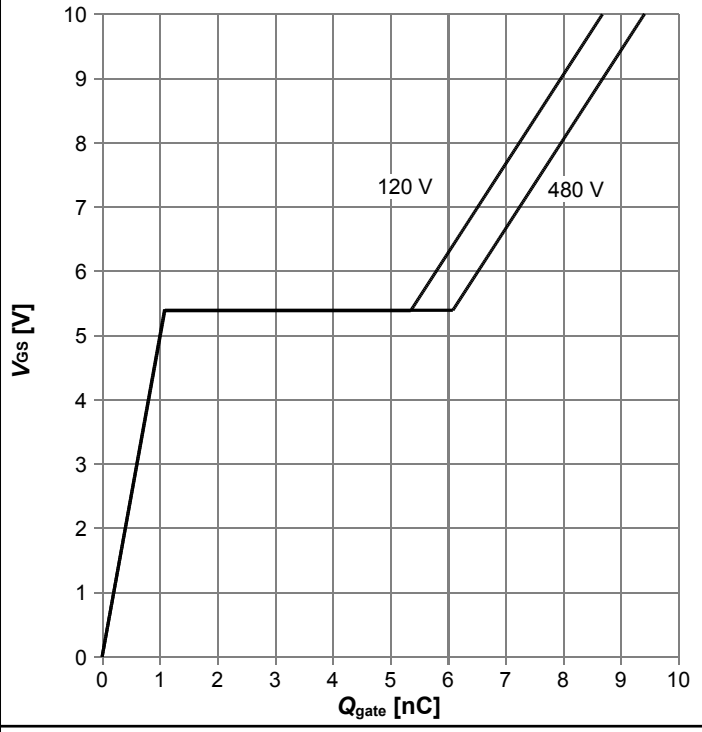

$R_{DS(on)}=f(T_j)$; $I_D=1.1$ A; $V_{GS}=10$ V

**Diagram 9: Typ. transfer characteristics**



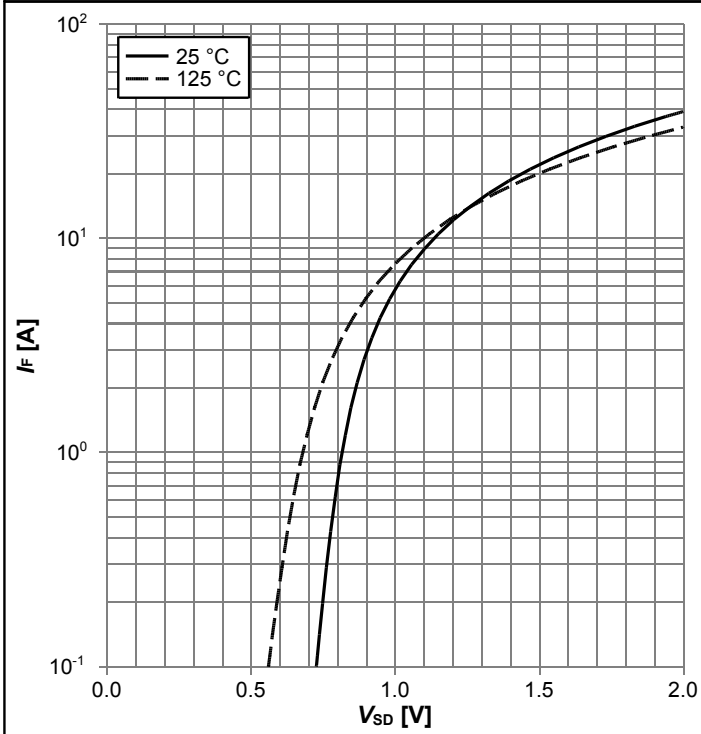

$I_D$=f($V_{GS}$); $V_{DS}$=20V; parameter: $T_j$

**Diagram 10: Typ. gate charge**



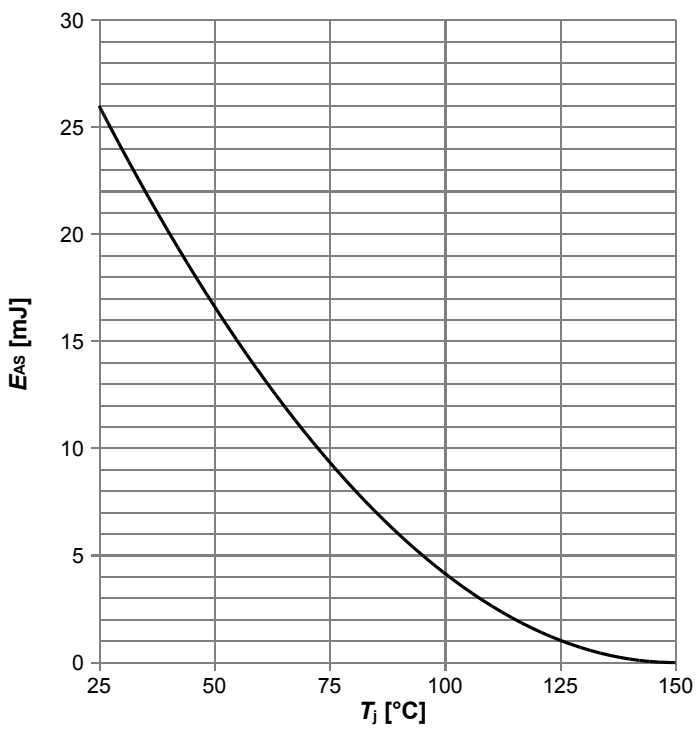

$V_{GS}$=f($Q_{gate}$); $I_D$=1.4 A pulsed; parameter: $V_{DD}$

**Diagram 11: Forward characteristics of reverse diode**



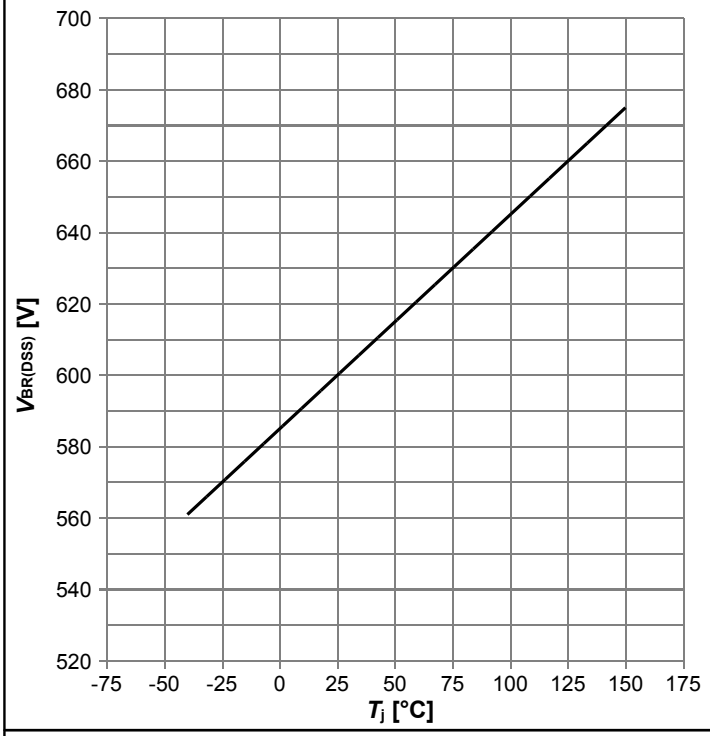

$I_F$=f($V_{SD}$); parameter: $T_j$

**Diagram 12: Avalanche energy**



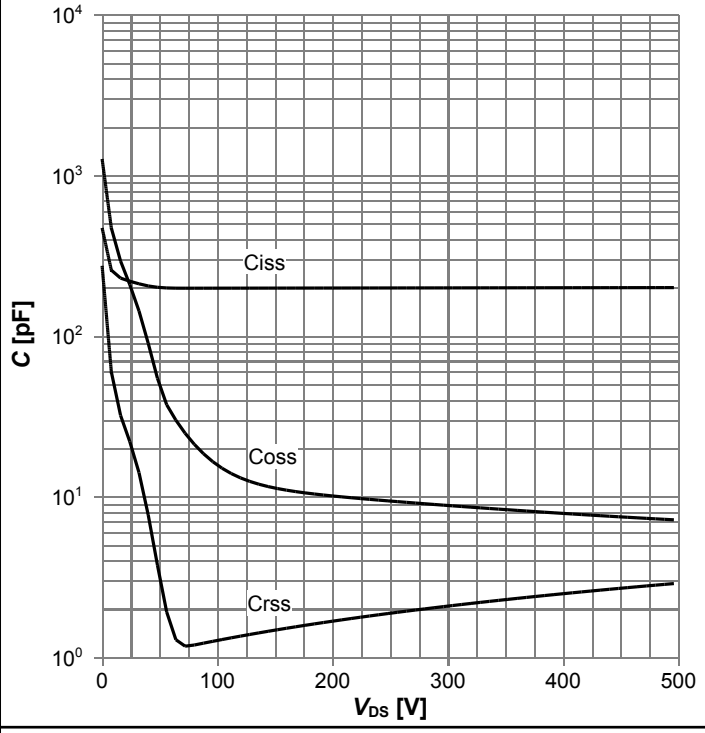

$E_{AS}$=f($T_j$); $I_D$=0.6 A; $V_{DD}$=50 V

**Diagram 13: Drain-source breakdown voltage**



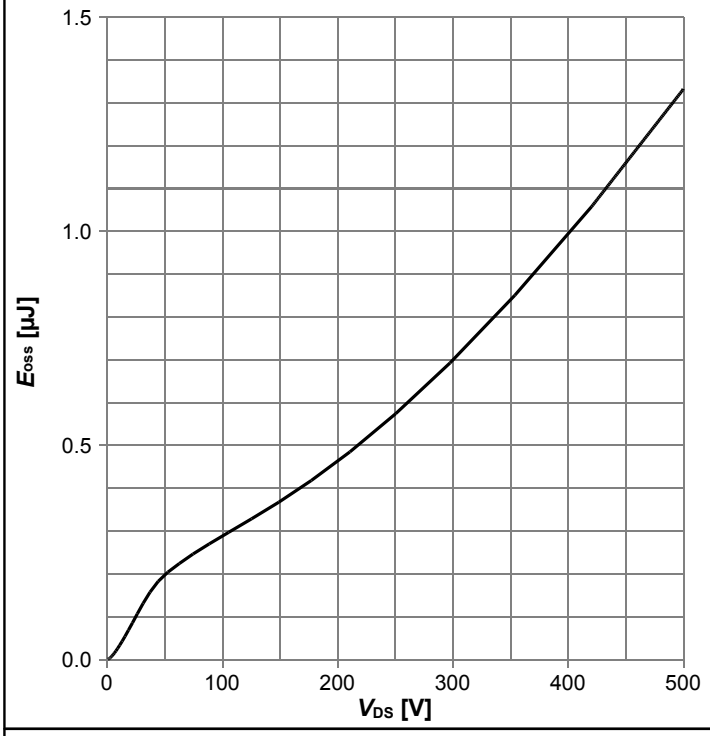

$V_{BR(DSS)}$=f($T_j$); $I_D$=0.25 mA

**Diagram 14: Typ. capacitances**




$C$=f($V_{DS}$); $V_{GS}$=0 V; $f$=1 MHz

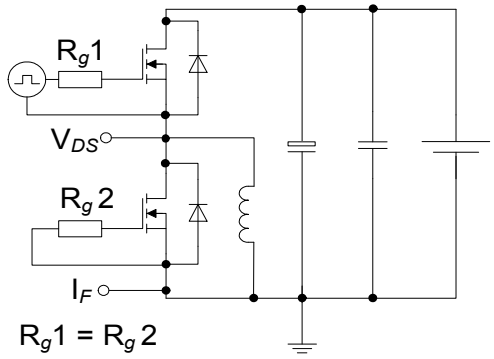
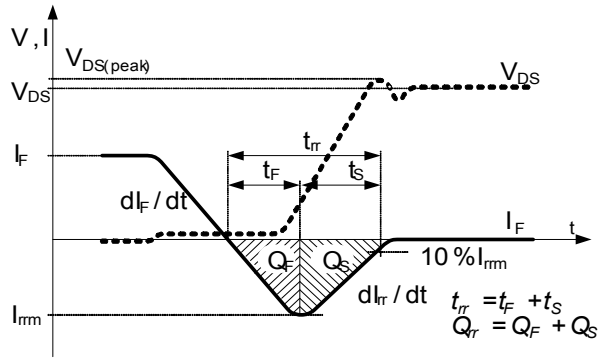
**Diagram 15: Typ. Coss stored energy**




$E_{oss}$=f($V_{DS}$)

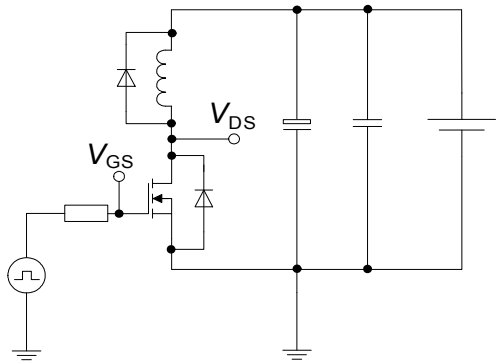
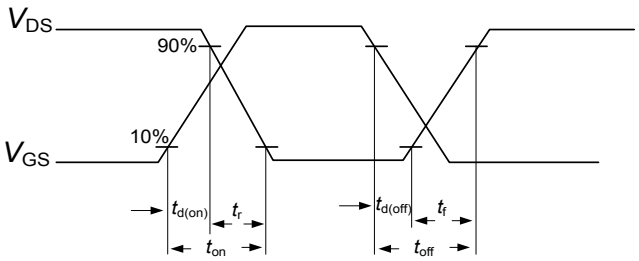
# 5 Test Circuits

## Table 8 Diode characteristics

| Test circuit for diode characteristics | Diode recovery waveform |
|---|---|
|  |  |

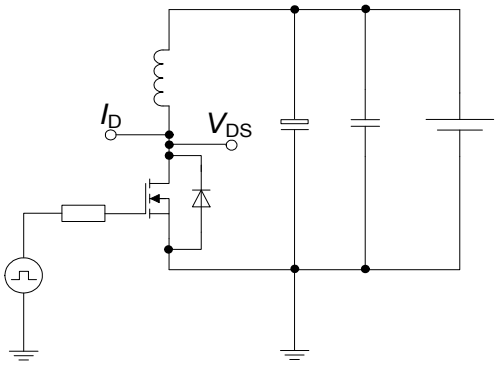
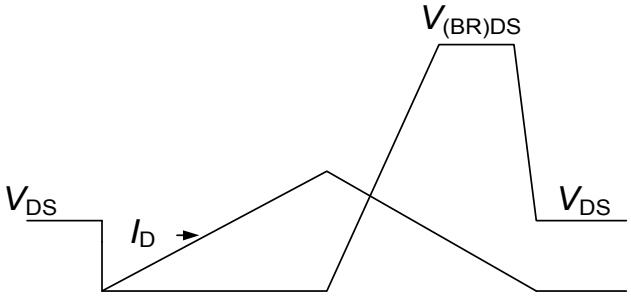


## Table 9 Switching times

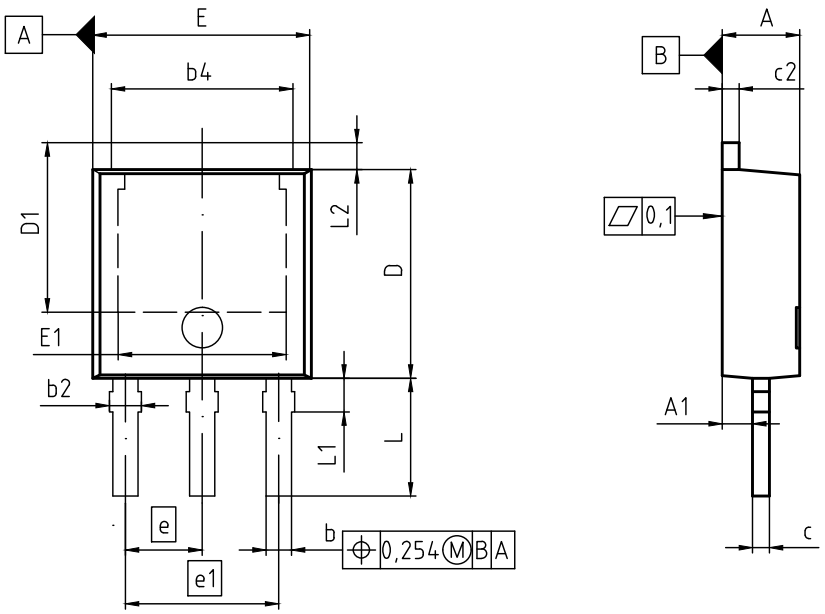
| Switching times test circuit for inductive load | Switching times waveform |
|---|---|
|  |  |



## Table 10 Unclamped inductive load

| Unclamped inductive load test circuit | Unclamped inductive waveform |
|---|---|
|  |  |

# 6 Package Outlines




| DIM | MILLIMETERS | | INCHES | |
|---|---|---|---|---|
| | MIN | MAX | MIN | MAX |
| **A** | 2.18 | 2.40 | 0.086 | 0.094 |
| **A1** | 0.80 | 1.14 | 0.031 | 0.045 |
| **b** | 0.64 | 0.89 | 0.025 | 0.035 |
| **b2** | 0.65 | 1.15 | 0.026 | 0.045 |
| **b4** | 4.95 | 5.50 | 0.195 | 0.217 |
| **c** | 0.46 | 0.59 | 0.018 | 0.023 |
| **c2** | 0.46 | 0.89 | 0.018 | 0.035 |
| **D** | 5.97 | 6.22 | 0.235 | 0.245 |
| **D1** | 5.04 | 5.55 | 0.198 | 0.219 |
| **E** | 6.35 | 6.73 | 0.250 | 0.265 |
| **E1** | 4.60 | 5.21 | 0.181 | 0.205 |
| **e** | 2.29 | | 0.090 | |
| **e1** | 4.57 | | 0.180 | |
| **N** | 3 | | 3 | |
| **L** | 3.00 | 3.60 | 0.118 | 0.142 |
| **L1** | 0.80 | 1.25 | 0.031 | 0.049 |
| **L2** | 0.88 | 1.28 | 0.035 | 0.050 |

**DOCUMENT NO.**
Z8B00003329

**SCALE**
0 2.0 4mm

**EUROPEAN PROJECTION**

**ISSUE DATE**
21-10-2015

**REVISION**
06

**Figure 1 Outline PG-TO 251, dimensions in mm/inches**

# 7 Appendix A

## Table 11 Related Links

- **IFX CoolMOS™ CE Webpage:** www.infineon.com
- **IFX CoolMOS™ CE application note:** www.infineon.com
- **IFX CoolMOS™ CE simulation model:** www.infineon.com
- **IFX Design tools:** www.infineon.com

## Revision History

IPS60R1K5CE

**Revision: 2016-02-26, Rev. 2.0**

| Previous Revision | | |
|---|---|---|
| Revision | Date | Subjects (major changes since last revision) |
| 2.0 | 2016-02-26 | Release of final version |

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